Event Selection and Reconstruction in PandaX

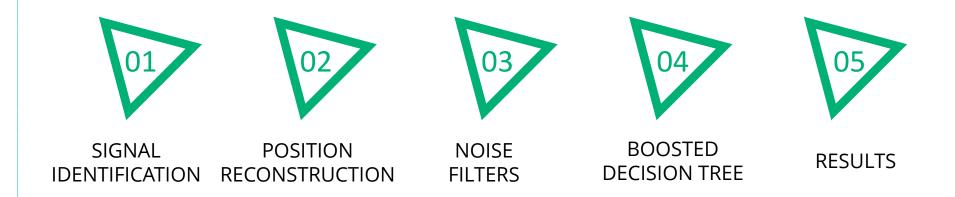
谢鹏伟

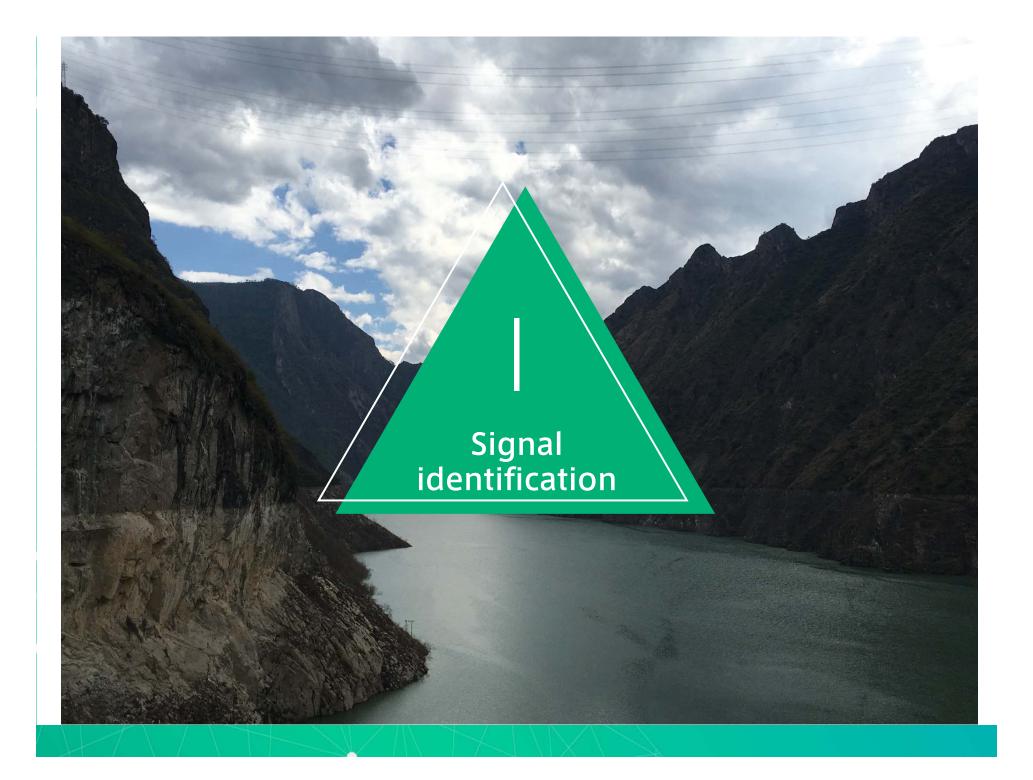
上海交通大学





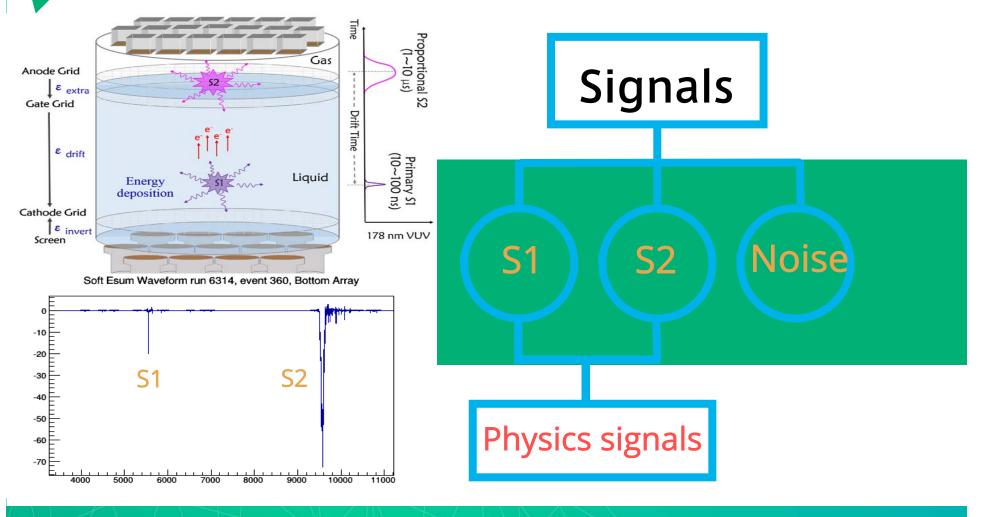
CONTENTS





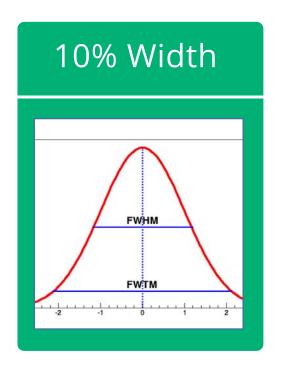


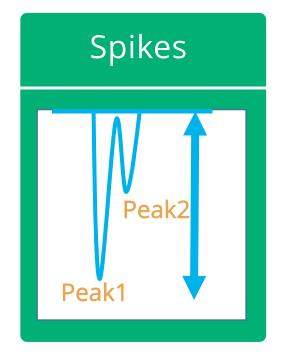
SIGNAL IDENTIFICATION



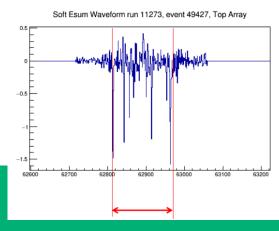


S1/S2 DIFFERENTIAL VARIABLES





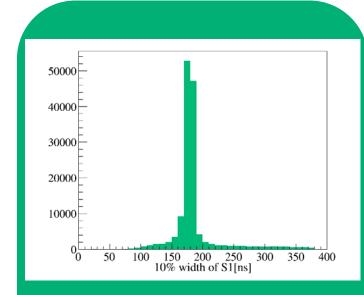
Single electron S2



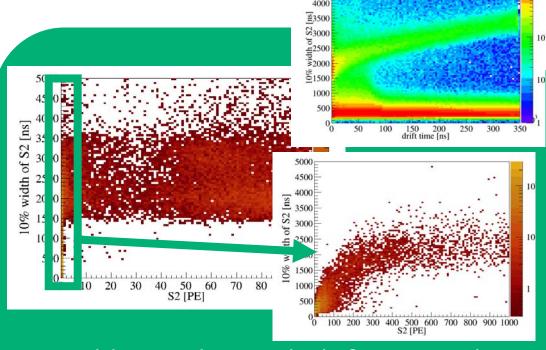
- Normally, S1 is narrow than S2.
- For small S2, use number of spikes to identify them.



S1/S2 DISCRIMINATION



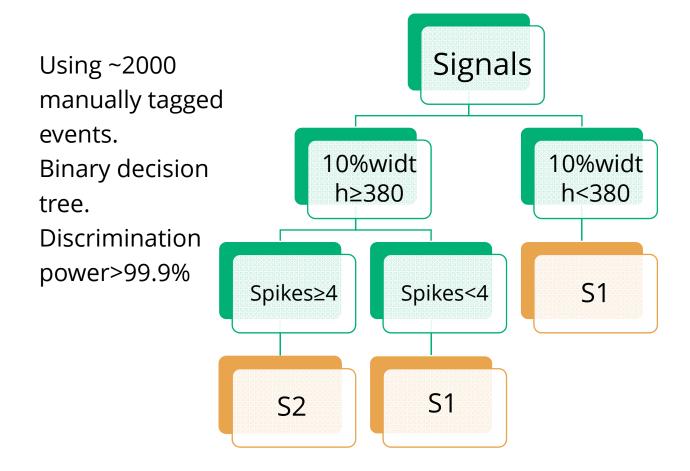
10% width of S1 centers at ~180ns



S2 width correlate with drift time and gas gap. For small s2, the 10% width do not work anymore.

01

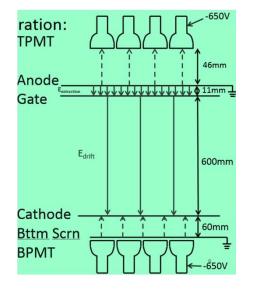
S1/S2 DISCRIMINATION

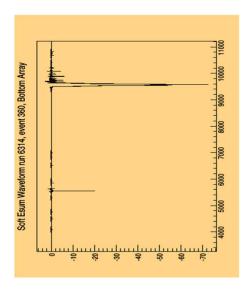


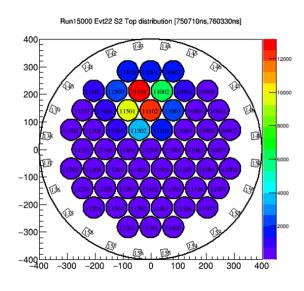


02

Position Reconstruction

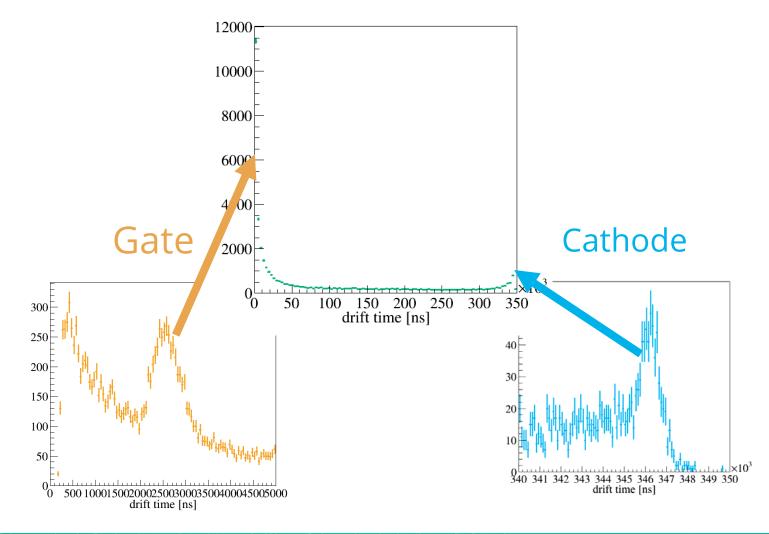






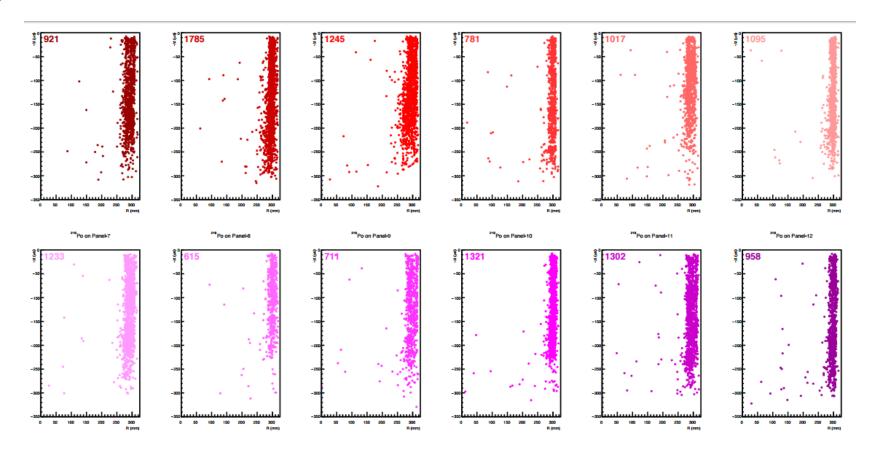
Separation between S2 and S1

X,Y: Center of Gravity X,Y: Template Matching X,Y:
Photon
acceptance
function

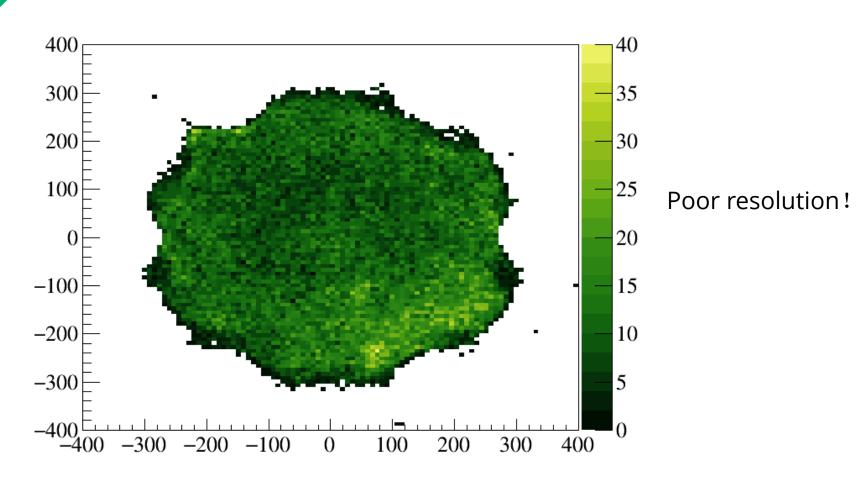




²¹⁰Po ON TEFLON WALL



CENTER OF GRAVITY

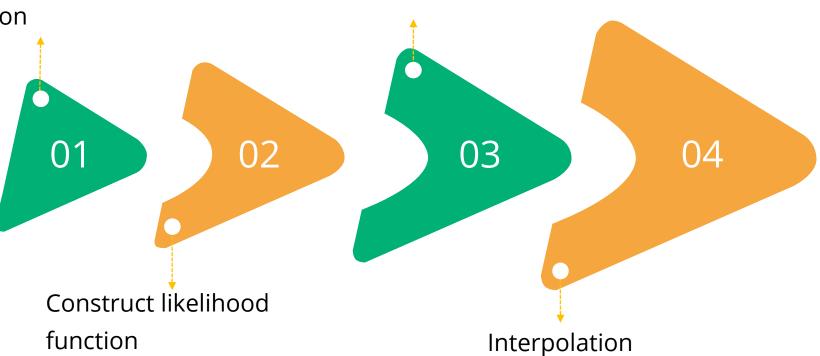


02

TEMPLATE MATCHING

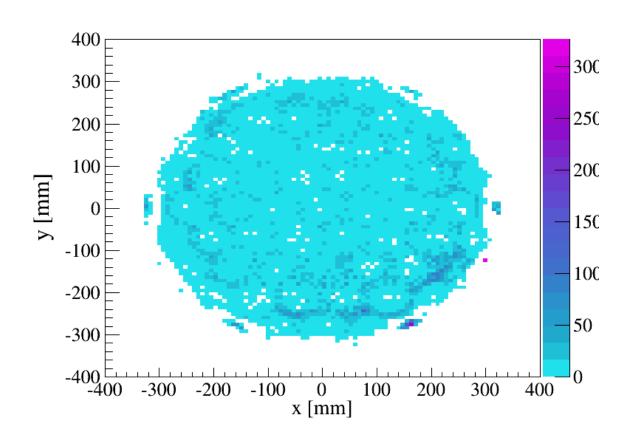
Generate massive templates from light simulation

Find the maximum likelihood number



$$L(p_i; n_i) = \prod_{i=1}^{r} p(n_i) = \prod_{i=1}^{r} \frac{e^{-Np_i}(Np_i)^{n_i}}{n_i!}$$

TEMPLATE MATCHING



Poor construction for fringe events.

5.5mm for S2~1000PE

Was selected in phase-i(1-inch PMTs in top array)

PHOTON ACCEPTANCE FUNCTION

Difficulties for position construction

1 3" PMT

optimizing photon collection, but naively causing coarse quantization

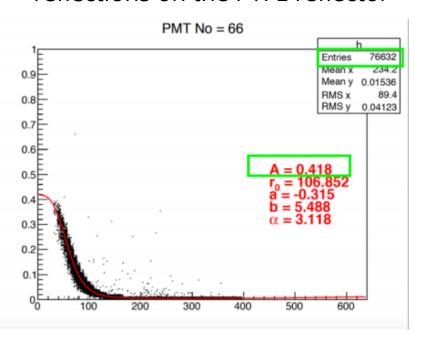
Procedures for PAF

1) Fit function for PAF, the input position is from COG

$$\eta(r) = A \cdot \exp\left(-\frac{a \cdot \rho}{1 + \rho^{1-\alpha}} - \frac{b}{1 + \rho^{-\alpha}}\right), \quad \rho = \frac{r}{r_0}$$

Complicated optics

particularly due to the photon reflections on the PTFE reflector



PHOTON ACCEPTANCE FUNCTION

- 2) Maximum likelihood to determine a new position
- 3) Iterations

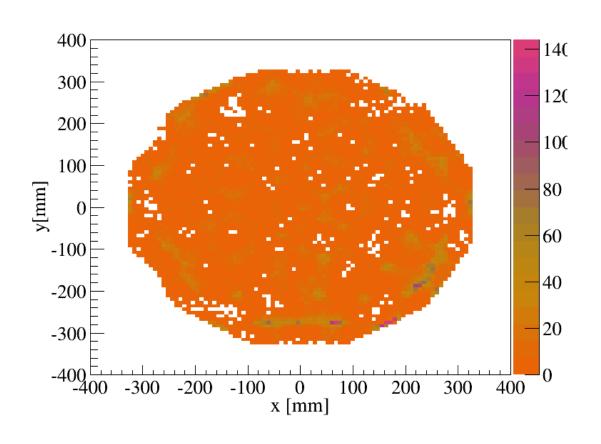
$$ec{r}^{(0)} = ec{r}_{\mathrm{CoG}}$$
 $\eta_i^{(1)} \longrightarrow ec{r}^{(1)}$
 $\eta_i^{(2)} \longrightarrow ec{r}^{(2)}$
 \vdots
Converge

Events Distribution from LRF[®] Position

Events Distribution from LRF[®]

V. N. Solovov *et al, IEEE* doi: 10.1109/TNS.2012.2221742

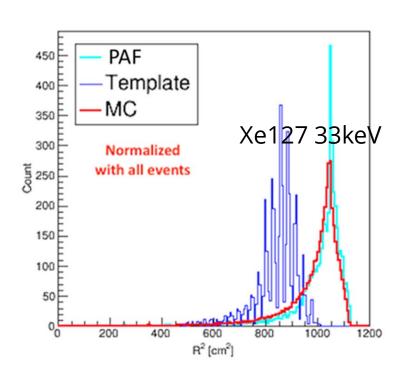
PHOTON ACCEPTANCE FUNCTION

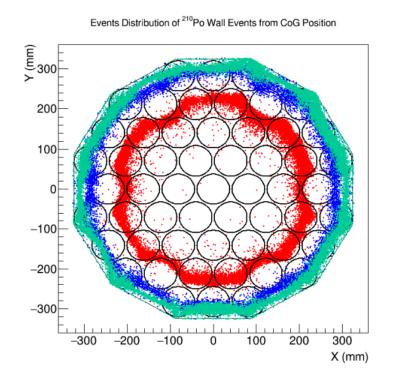


With consideration of reflection.

02/

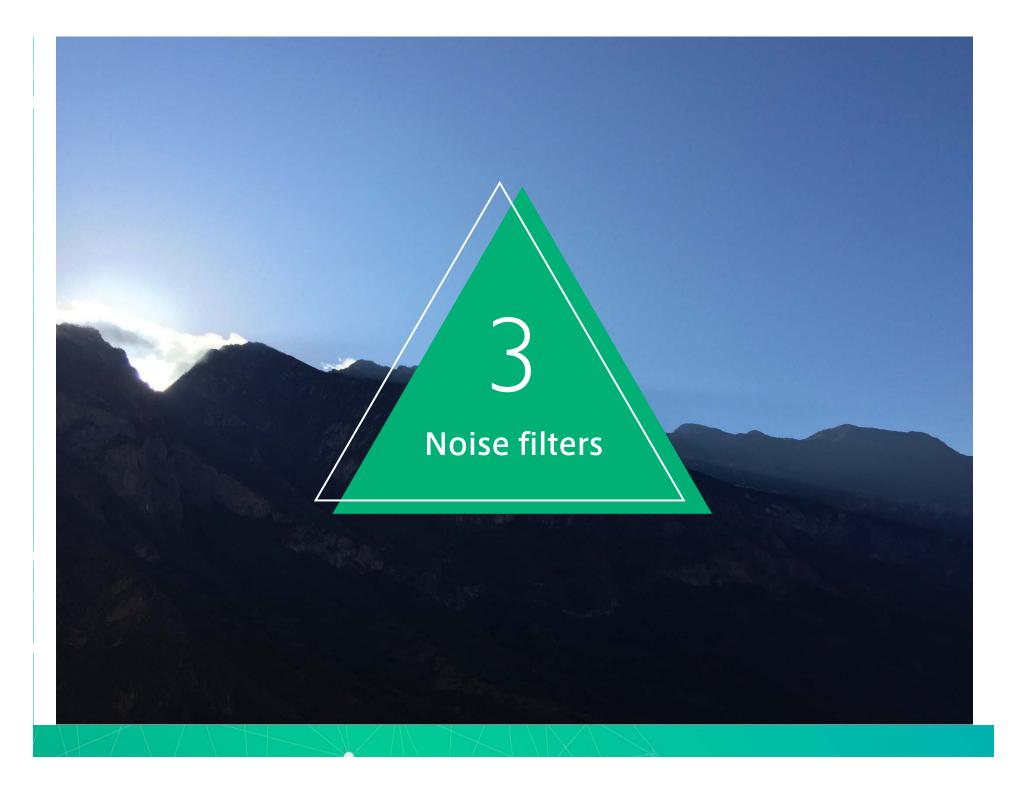
COMPARISION OF THREE WAYS





Choose PAF!

To be improve: fix saturation.





03 QUALITY CUTS

Reject runs with shot runtime, hot spot etc.

Manually remove files with abnormal trigger rate, dark rate and efficiency

Remove triggers within 10 ms to previous triggers



NOISE REMOVAL

S1 CONCIDENCE

s1 charge vs. fired pmts

S1 PATTERN

Charge from largest bottom channel vs total charge

S1NOISEFILTERS

Remove ripple-like electronic noise

S2T/BRATIO

Remove abnormal S2

SELECTION WINDOW

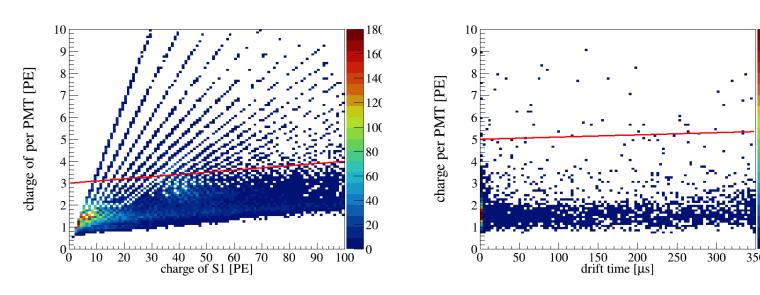
Random coincident
S1 and single
electron S2

OTHER

"S1" number<3 etc



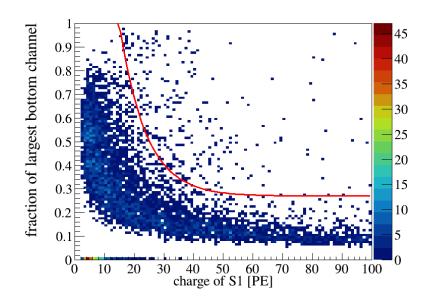
S1 COINCIDENCE CUT

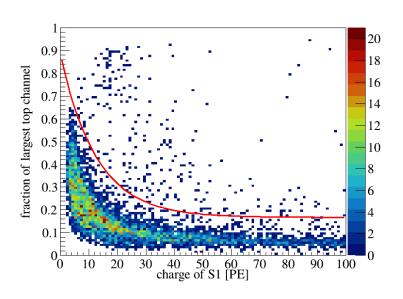


S1 charge per PMT vs S1 charge(left) and drift time(right).



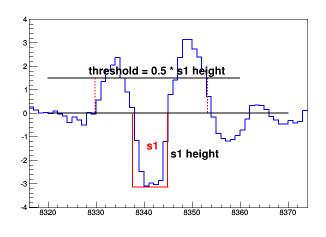
S1 PATTERN CUT





Applied in phase-I to remove X-events.

WAVY S1 FILTERS

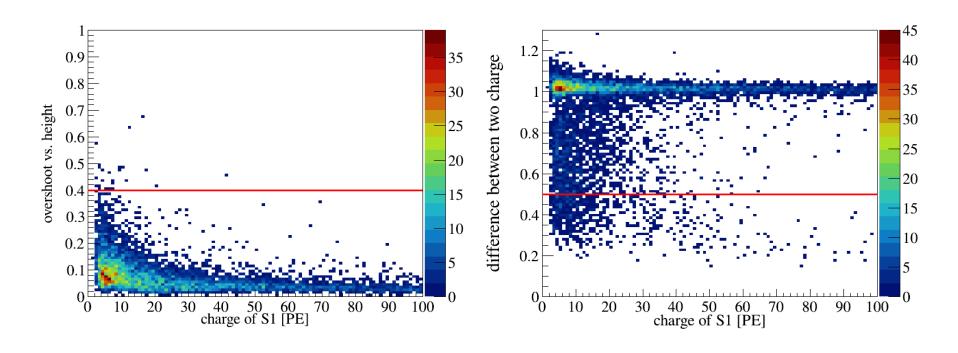


Used to be the most serious noise Two cuts are applied to remove those wavy noise.

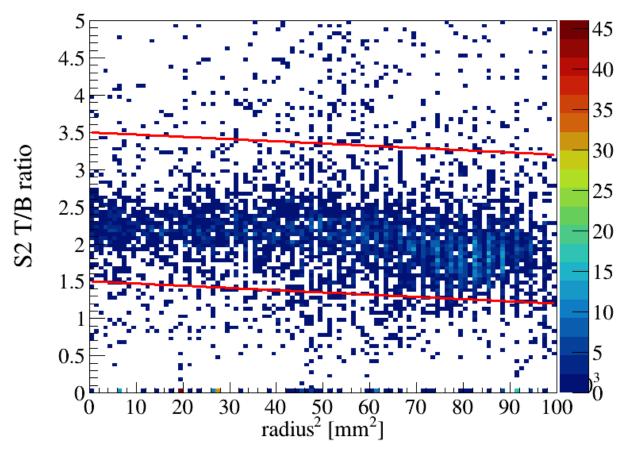
- Based on overshoot
 Less than 0.4 of the height of S1
- 2) Based on difference of charge calculation from two methods
 - Charge calculated by integrating PMT hits.
 - Charge calculated by integrating summed waveform.



WAVY S1 FILTERS



S2 T/B RATIO



The average number is 2 which conforms with MC.

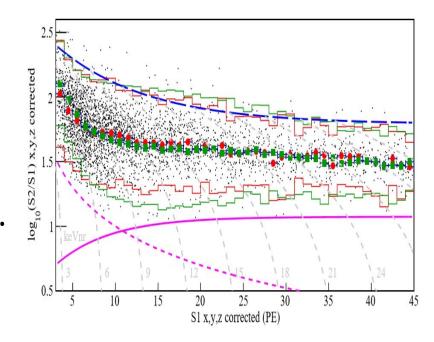
03

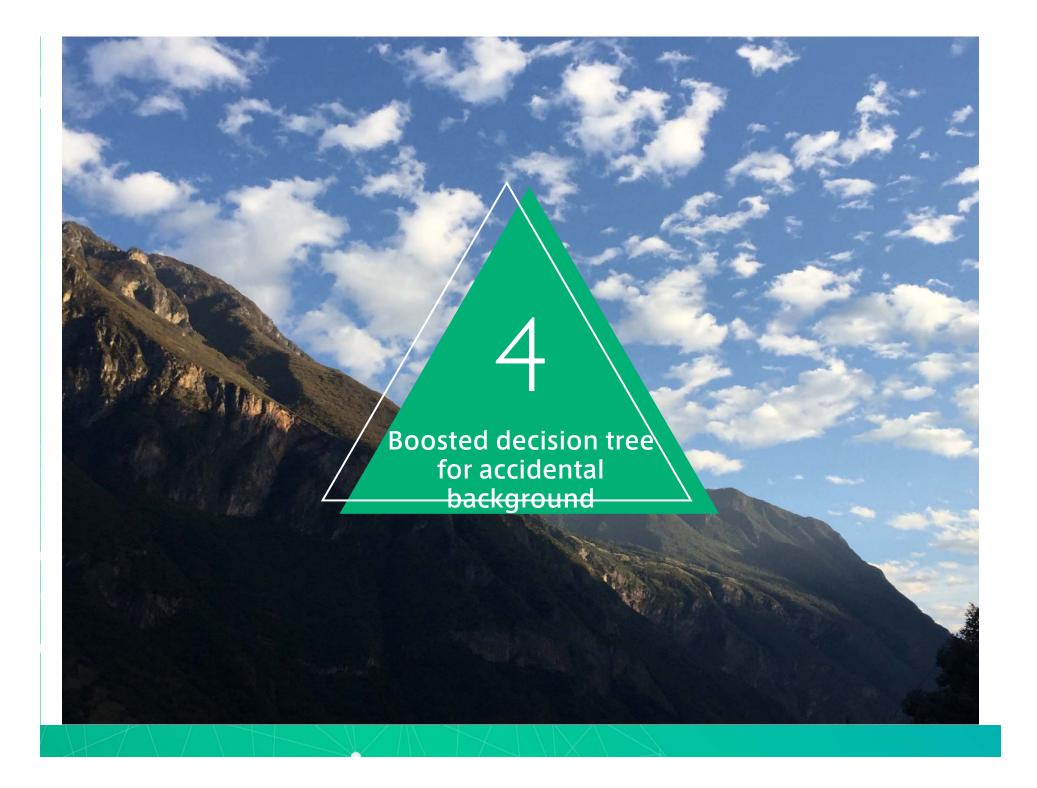
SELECTION WINDOW

S1: 3 fired PMTs, [3,45] PE Limited by dark rates

S2: [100,10000] PE Limited by floating small S2.

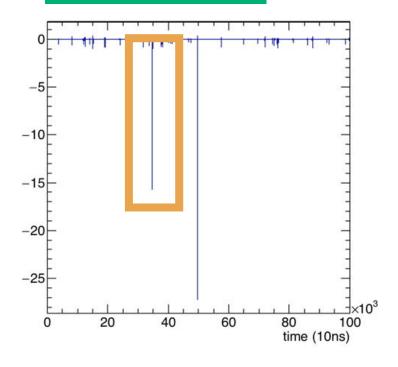
NR 99.99% Acceptance line



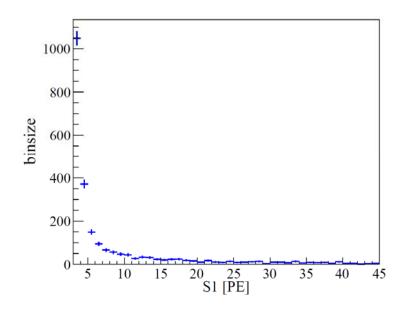




Isolated S1



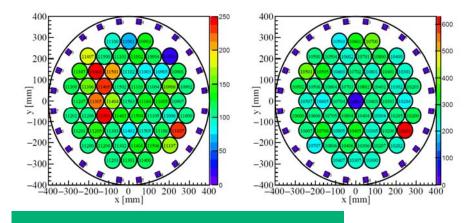
Spectrum



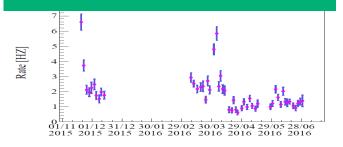
Search "s1" before s1-only events



Collective pattern



Evolution



Cause

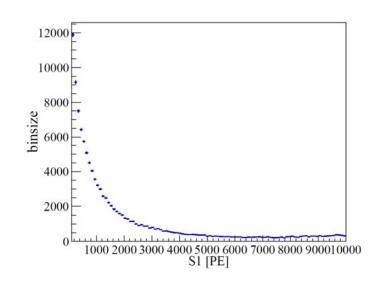
PMT Sparking Electrodes Sparking S1 from "dead" region etc.

Isolated S2

-10 -15 -20 -25 -30F 0 10 20 30 40 50 60 70 80 90 100 time (10 ns)

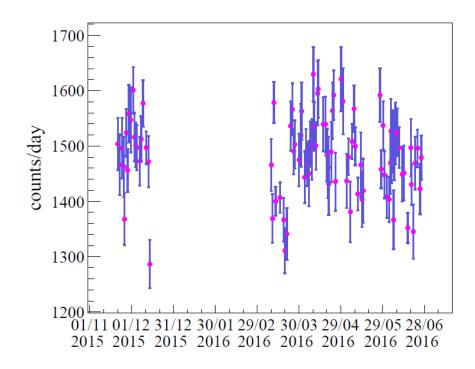
No s1 before s2

Spectrum





Evolution



Cause

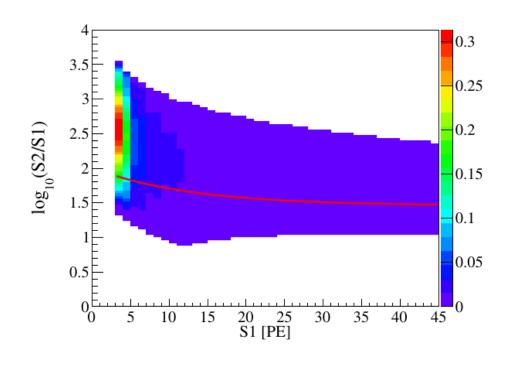
Real S1 quenched.

Lots of events
generated from gate



RANDOM COINCIDENT EVENTS

Randomly pairing



Isolated S1:1.8HZ

Isolated S2:1500/day

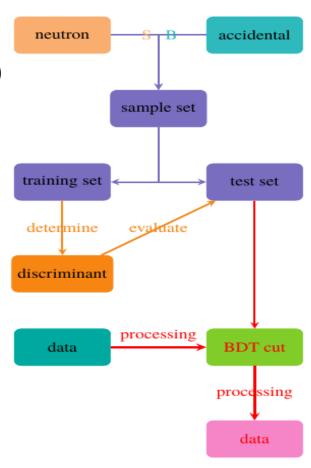
Accidental events: 4.3

in 98.7 days

04

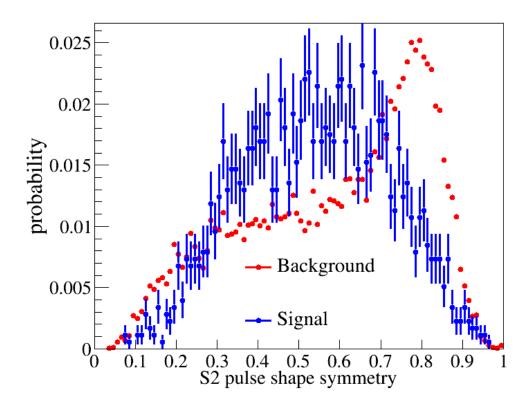
BOOSTED DECISION TREE

- Seek additional suppression of accidental background using a multivariate approach (BDT)
- Training and test samples: randomly paired coincident events (background) and AmBe low energy events (signal)
- Variables:
 - S1 charge, S2 charge, drift time
 - S2 pulse shape symmetry, S2 Top/Bottom ratio
 - S2 width, S2 10% width, S2 rising edge
 - S2 charge pattern
 - S1 charge pattern
 - "gate charge"



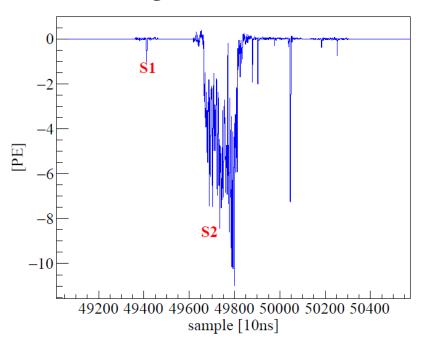
BOOSTED DECISION TREE

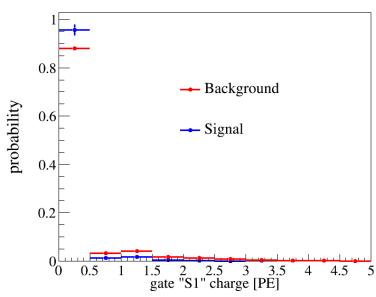
S2 pulse shape symmetry



BOOSTED DECISION TREE

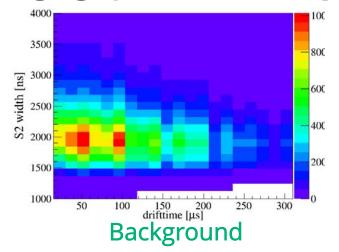
"Gate charge"

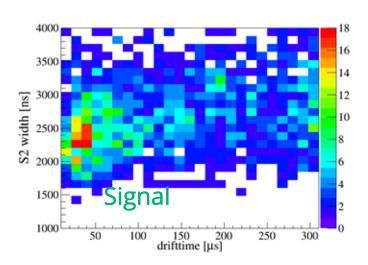




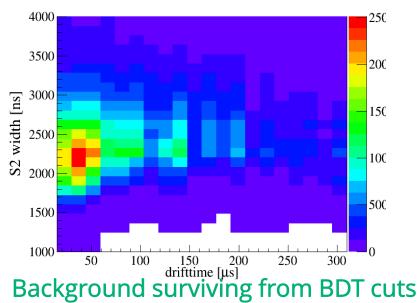


BOOSTED DECISION TREE

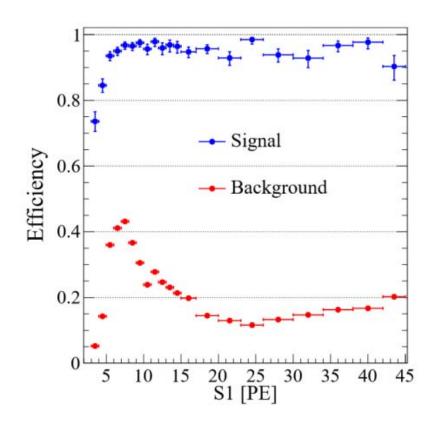




- Accidental S1 and S2 lack intrinsic correlations
- Single S2 likely originated from the gate grid (small width)

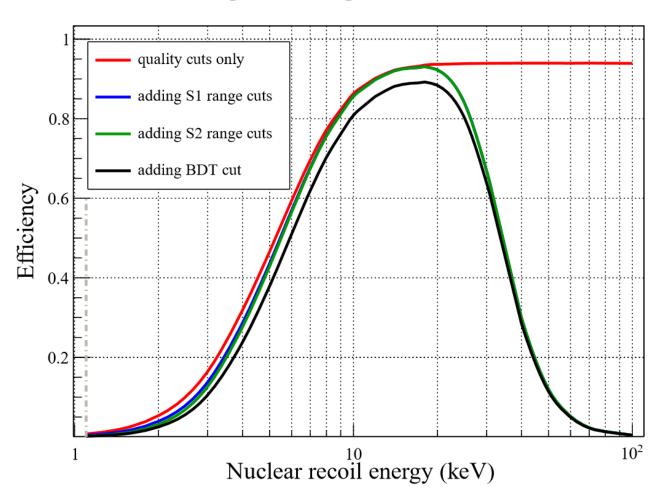


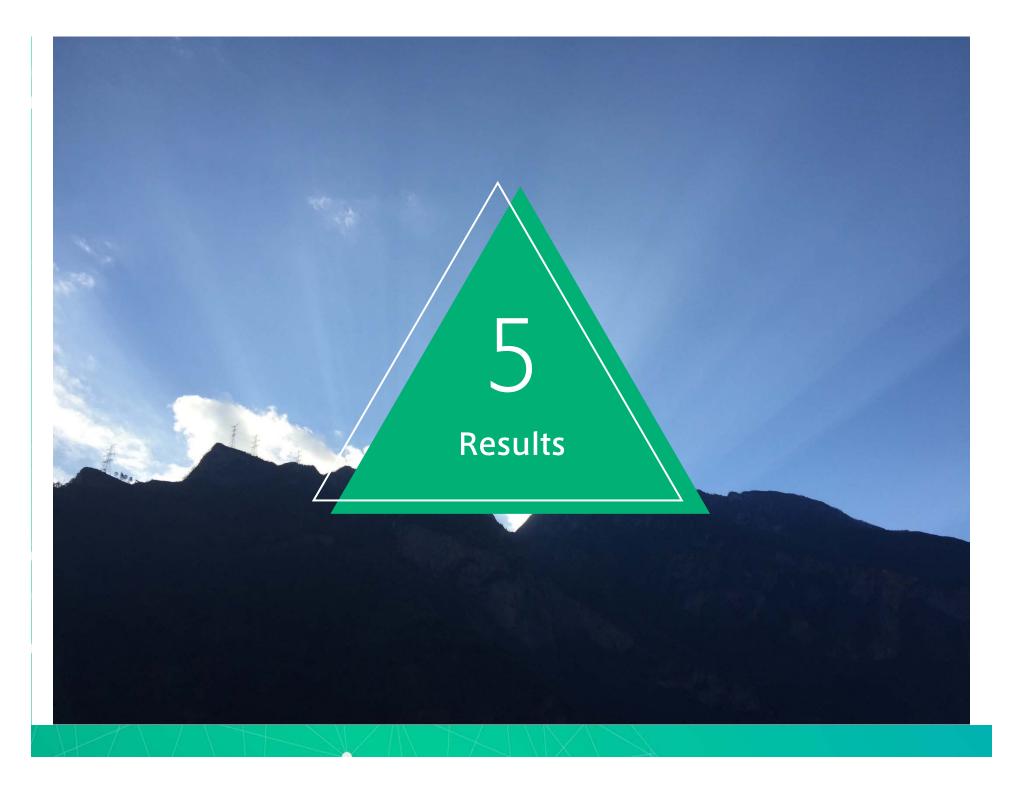
BDT EFFICIENCY



BDT removes the accidental events by more than a factor of 3, while maintaining an average 90% efficiency

NR EFFICIENCY

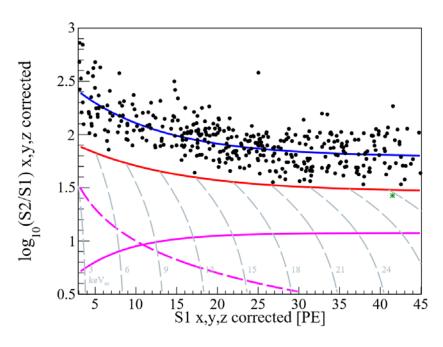






05 FINAL CANDIDATES

Cut	#Events	Rate[HZ]
All	24502402	3.56
Single site	9783090	1.42
Quality cuts	5160513	0.75
Low energy window	131097	1.91*10 ⁻²
Fiducial Volume	398	5.79*10 ⁻⁵
BDT cut	389	5.66*10 ⁻⁵



THANKS!